7th Thermo Fisher Scientific XPS Workshop

June 5th 2019 – June 7th 2019

Université de Versailles Saint-Quentin-en-Yvelines (Université Paris Saclay)
Campus des Sciences, 45 avenue des Etats-Unis,
78035 Versailles, France

AGENDA

Wednesday 5th June – Moderated by Damien Aureau		
Time	**Presentation**	**Speaker**
09:00	Registration	
09:30	CHARM3AT	François Ozanam, CHARM3AT
	XPS in Versailles - the Story of CEFS2 Center	Arnaud Etcheberry University of Versailles St Quentin
	About the quantitative semi-conductors Surfaces investigations	Arnaud Etcheberry University of Versailles St Quentin
	XPS as a pivotal surface analytical tool in material sciences and the need to consider method-induced damage	Michael Bruns, Karlsruhe Institute of Technology
	Influence of etching conditions on the composition profile of an MgON-based material	Frederic Georgi, CEMEF, Mines Paris Tech
11:00	Coffee break	
11:30	Interfaces in Halide Perovskite Photovoltaics	Philip Schulz, IPVF Paris
	Title TBA	Anna Regoutz, Imperial College London
	In situ characterisation of JM catalysts using AP-XPS	Tugce Erden, Johnson Matthey
	New Developments (and some old favourites) in XPS	Tim Nunney, Thermo Fisher Scientific
13:15	Lunch	
15:15	Palace of Versailles visit	
19:30	Dinner sponsored by Thermo Fisher Scientific - Café Marion	

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Thursday 6th June – Moderated by Richard White		
Time	**Presentation**	**Speaker**
09:00	Multiple technique analysis of perovskite materials used in battery and fuel cell components	Robin Simpson, Thermo Fisher Scientific
	Advanced surface analysis of SrVO3 and SrTiO3 functional oxides for future microelectronic devices	Yoan Bourlier, University of Versailles St Quentin
	Surface Analysis of Wood: Correlation of XPS and ToF-SIMS Data with Growth-Rings, Orientation, Age and Species?	John Watts, University of Surrey
10:20	Coffee break	
11:00	On the X-ray photoelectron spectroscopy analysis of LiNixMnyCozO2 battery electrodes	Alex Bondarchuk, INL Braga
	The IMPACT Project: Merging academic research and industrial applications. Quasi in situ advanced characterizations for materials upfront studies and process development in microelectronics	Bernard Pelissier, CNRS-LTM Grenoble
	Microbiologically Influenced Corrosion mechanisms of 2304 Duplex Stainless Steel during the Pseudoalteromonas NCIMB 2021 biofilm growth: a ToF-SIMS and XPS characterization	Sandrine Zanna, IRCP-Chimie-Paristech
12:20	Lunch	
14 :00	The application of electron spectroscopy for the study of surfaces & interfaces for energy storage materials	Dominique Foix, IPREM Pau
	New fields of application for quantitative chemical state imaging with XPS mapping	Vanessa Trouillet, Karlsruhe Institute of Technology
	XPS and UPS investigations of electro-grafted molecules onto surfaces	Christian Perruchot, ITODYS Paris
	XPS & Raman Spectroscopy – Structure & Spectra	Richard White, Thermo Fisher Scientific
15:30	Coffee break	
16:00	Closing remarks	

Friday 7th June	
Time	**Presentation**
09:00	Thermo Scientific Avantage software training & instrumentation demonstrations
10:30	Coffee break
11:00	Thermo Scientific Avantage software training & instrumentation demonstrations
12:30	End of Training Session

Organization :

Mathieu Fregnaux - Université de Versailles Saint-Quentin

Damien Aureau - Université de Versailles Saint-Quentin

Pascal Bordeau – Thermo Fisher Scientific

Tim Nunney – Thermo Fisher Scientific

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